

<b>Notice of References Cited</b>	Application/Control No. 09/935,493	Applicant(s)/Patent Under Reexamination SMALLEY ET AL.	
	Examiner Elena Tsoy	Art Unit 1762	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0092613	07-2002	Kuper, Cynthia A.	156/296
	B	US-5,560,898	10-1996	Uchida et al.	423/461
	C	US-6,576,341	06-2003	Davey et al.	428/376
	D	US-5,653,996	08-1997	Hsu, Chung C.	424/450
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 989579 A2	03-2000	European Patent	BOWER et al.	H01J 01/30
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Tohji et al , Fullerene Sci. Technol. 7 (1999) 665-679
*	V	Shaffer et al, Adv. Mater. 1999, 11(11), 937-941x
	W	Riggs et al, J. Phys. Chem. B 2000, 104, 7071-7076
	X	Riggs et al, J. Am. Chem. Soc. 2000, 122, 5879-5880

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.